## Notice of References Cited Application/Control No. 10/552,540 Examiner Patrick D. Niland Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A ·	US-5,639,808	06-1997	Coggio et al.	523/452
	В	US-		·	
	O	US-			
	Þ	US-			
	Е	US-			
	F	US-		·	
	G	US-		·	
	Н	US-			
	ŀ	US-			
	7	US-			
	Κ	US-			
	٦	US-			
	Σ	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06-264035(translation)	09-1994	JP	Shinji et al.	
	0					
	P					
	Q					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.